

WHAT IS CLAIMED IS:

- 1 1. A method, comprising:
2 determining if a memory is functional based on memory BIST data;
3 selecting a redundant memory section if a portion of the memory is determined to
4 be nonfunctional; and
5 determining if at least the selected redundant memory is functional according to a
6 BIST.
- 1 2. The method of claim 1, further comprising storing data indicating the selected
2 redundant memory section.
- 1 3. The method of claim 1, further comprising outputting a pass or fail signal based
2 on the determining if at least the selected redundant memory is functional according to a
3 BIST.
- 1 4. The method of claim 1, wherein the redundant memory section includes a column
2 or row.
- 1 5. The method of claim 1, wherein the redundant memory section includes a bit.
- 1 6. The method of claim 1, wherein the selecting selects a redundant memory section
2 from a redundant memory data structure.
- 1 7. The method of claim 6, further comprising updating the redundant memory data
2 structure to indicate that the selected redundant memory section is no longer redundant.

1 8. The method of claim 1, wherein the method is performed during a manufacturing
2 process.

1 9. The method of claim 1, wherein the method is performed during power up of an
2 integrated circuit.

1 10. A system, comprising:
2 means for determining if a memory is functional based on memory BIST data;
3 means for selecting a redundant memory section if a portion of the memory is
4 determined to be nonfunctional; and
5 means for determining if at least the selected redundant memory is functional
6 according to a BIST.

1 11. A system, comprising:
2 a BIST capable of determining if a memory is functional; and
3 self-adaptive logic, communicatively coupled to the BIST, capable of selecting a
4 redundant memory section if a portion of the memory is determined to be nonfunctional;
5 wherein the BIST is further capable of determining if at least the selected
6 redundant memory is functional.

1 12. The system of claim 11, further comprising a register communicatively coupled to
2 the self-adaptive logic and wherein the self-adaptive logic is further capable of storing
3 data indicating the selected redundant memory section in the register.

1 13. The system of claim 11, further comprising a pin and wherein the self-adaptive
2 logic is further capable of outputting a pass or fail signal based on the BIST

3 determination of the functionality of the selected redundant memory.

1 14. The system of claim 11, wherein the redundant memory section includes a
2 column or row.

1 15. The system of claim 11, wherein the redundant memory section includes a bit.

1 16. The system of claim 11, further comprising a redundant memory data structure
2 listing redundant memory sections and wherein the self-adaptive logic selects a redundant
3 memory section from the redundant memory data structure.

1 17. The system of claim 11, wherein the self-adaptive logic is further capable
2 updating the redundant memory data structure to indicate that the selected redundant
3 memory section is no longer redundant.

1 18. The system of claim 11, wherein the BIST and the self-adaptive logic function
2 during a manufacturing process.

1 19. The system of claim 11, wherein the BIST and the self-adaptive logic function
2 during power up of the system.